

Bernd Dehning
CERN BE-BI

Event

- Date 03.05.2015
 - beam dumped by monitor BLMQI.21R6.B1E10.MQ, 13.24.50
 - higher signal already observed in the whole octant, 13.24.30
 - change in HV current observed at 13.23.52

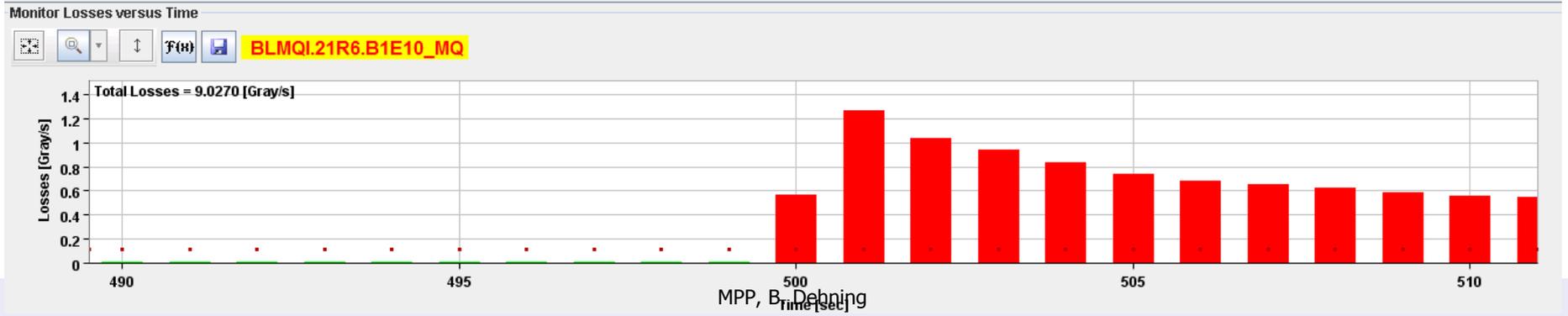
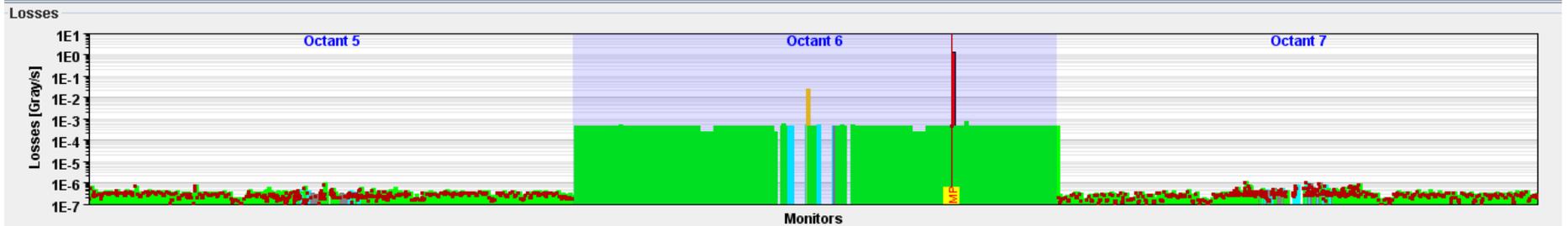
Unit: Gray/s Scale: Log Integration Time: 1.3 s Losses: Max Display: Acquisition

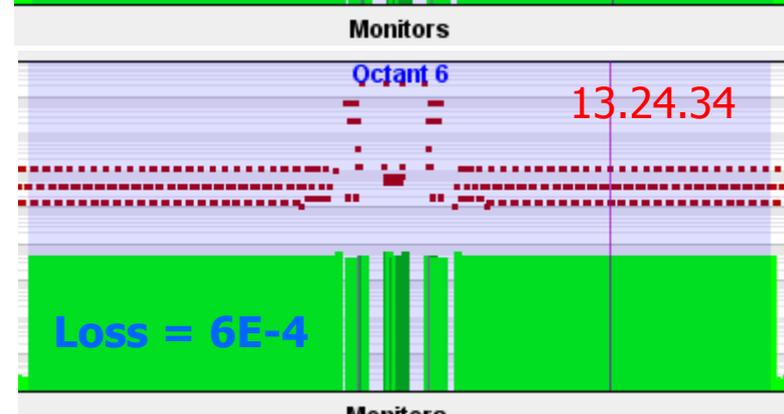
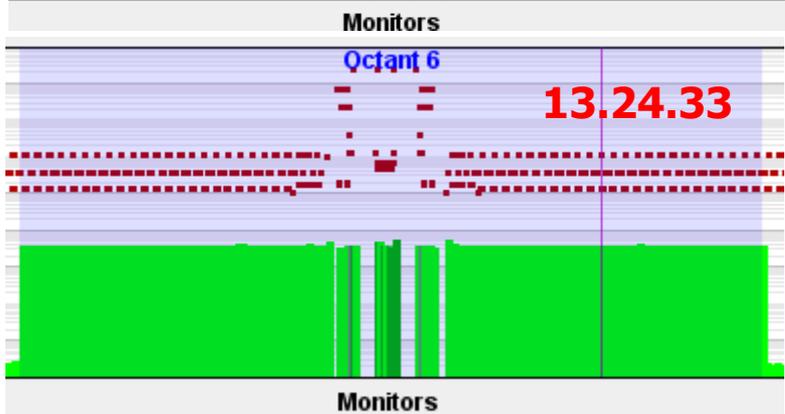
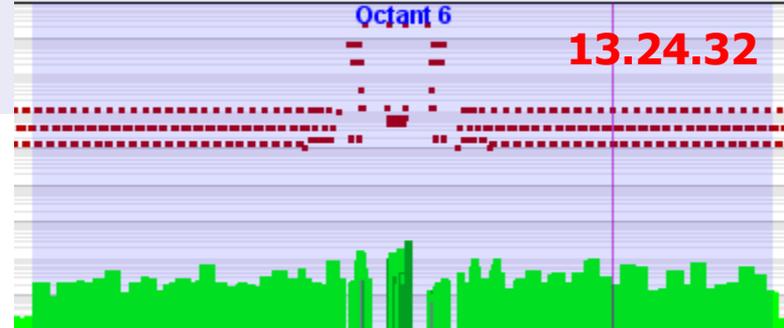
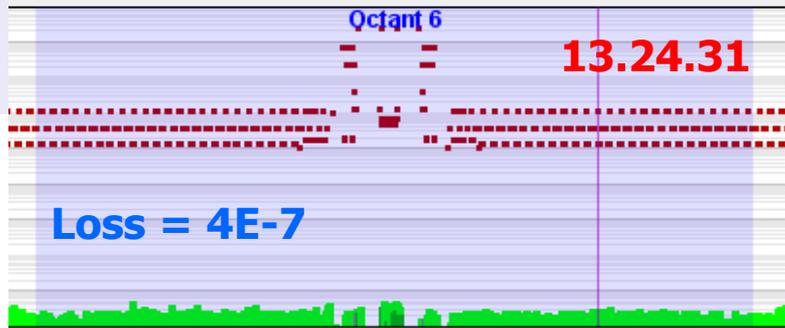
Octant Filter Sectors Filter Dump Filter List Filter Regex Filter Beam Permit Filter

Filter (1365 / 3929)

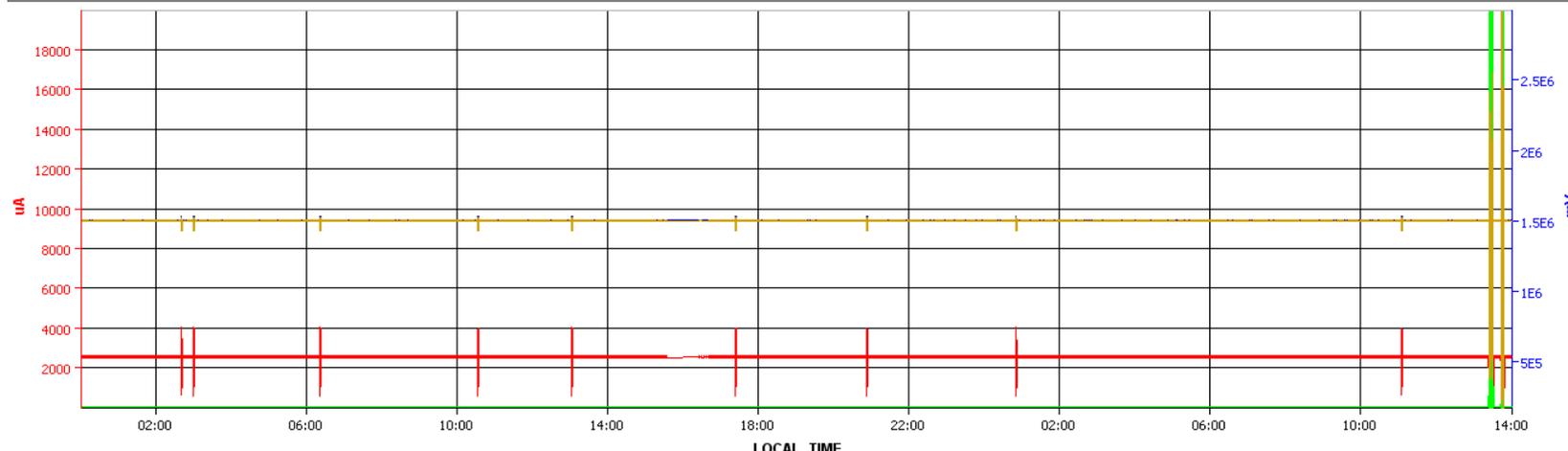
Monitor	40 us	80 us	320 us	640 us	2560 us	10 ms	82 ms	655 ms	1.3 s	5.2 s	20.9 s	83.8 s	Type	Section	Left Ri...	Octant	Beam
BLMQI.21R6.B1E10_MQ	OK	OK	OK	OK	OK	OK	Dump	Dump	Dump	Dump	Dump	Dump	<input checked="" type="checkbox"/> IC <input type="checkbox"/> LIC <input type="checkbox"/> FIC <input type="checkbox"/> SEM	<input checked="" type="checkbox"/> LSS <input checked="" type="checkbox"/> DS <input checked="" type="checkbox"/> ARC	<input checked="" type="checkbox"/> Left <input checked="" type="checkbox"/> Right	<input type="checkbox"/> 1 <input checked="" type="checkbox"/> 5 <input type="checkbox"/> 2 <input checked="" type="checkbox"/> 6 <input type="checkbox"/> 3 <input checked="" type="checkbox"/> 7 <input type="checkbox"/> 4 <input type="checkbox"/> 8	<input checked="" type="checkbox"/> Beam 1 <input checked="" type="checkbox"/> Beam 2 <input checked="" type="checkbox"/> Centre

03.05.2015 13:24:50

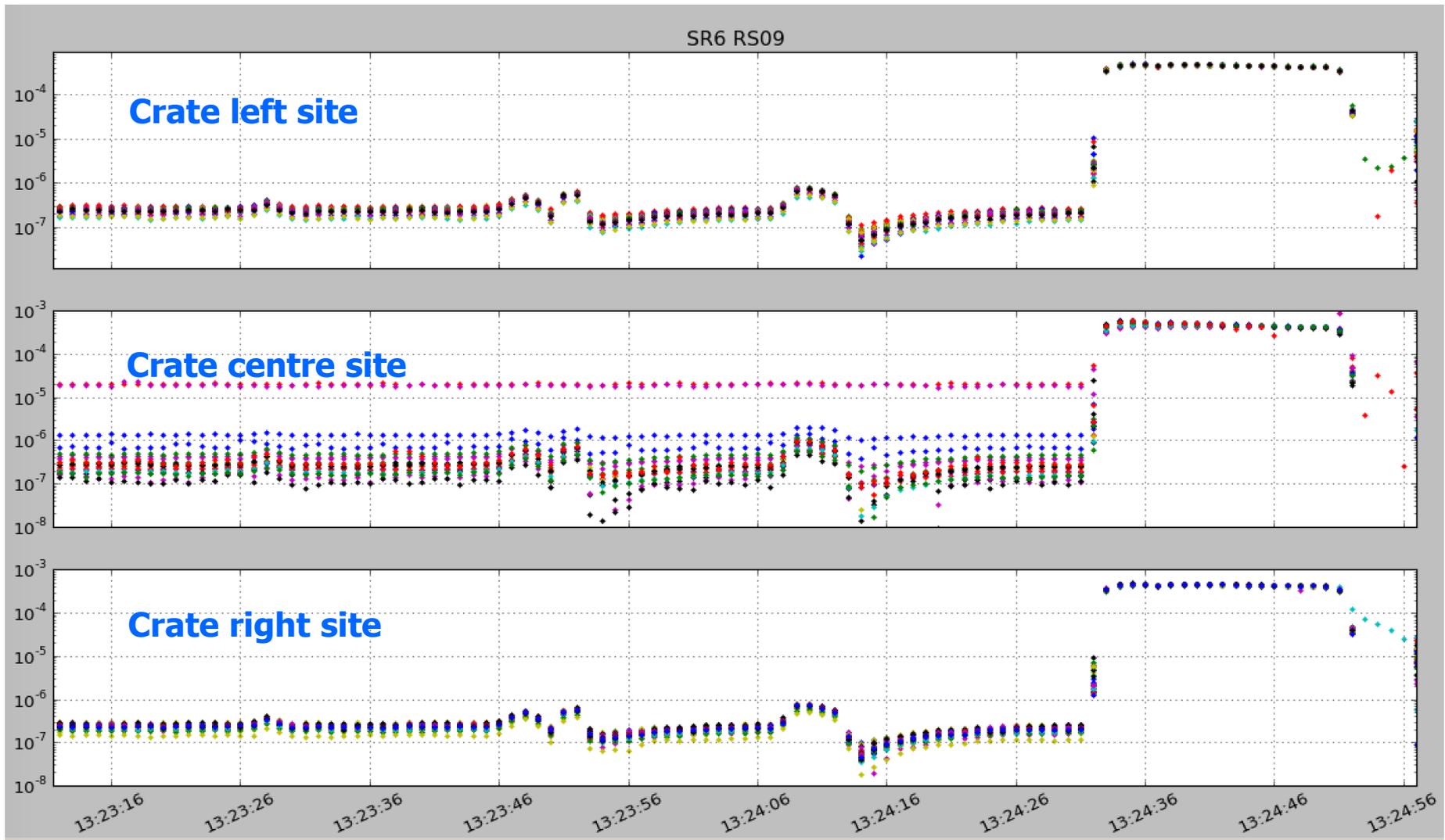




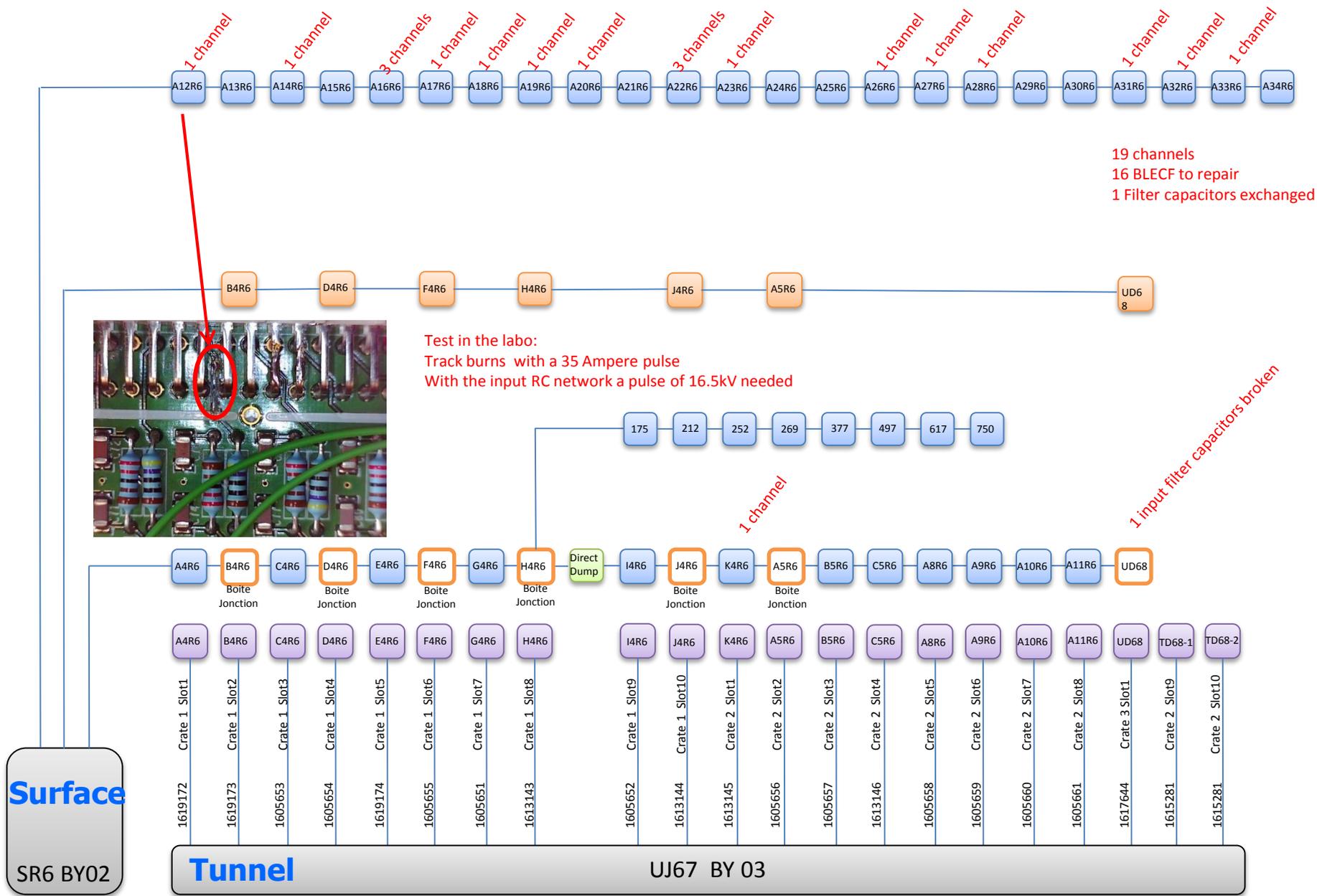
Timeseries Chart between 2015-05-02 00:00:00.000 and 2015-05-03 14:00:00.000 (LOCAL_TIME)

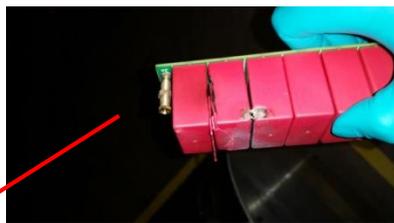
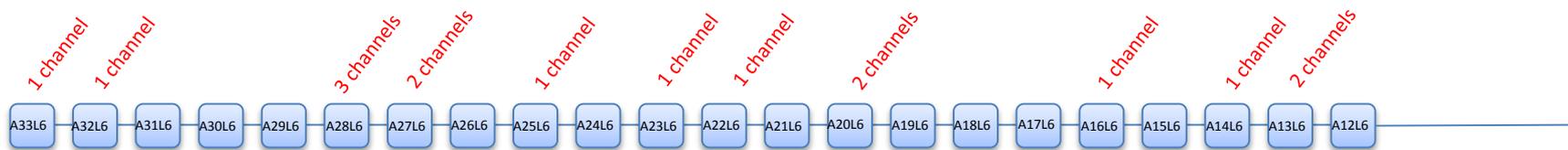


IP 6 beam loss signal - sum of 8 channels vs time



Same signal structure seen at all groups of monitors





1M HV resistor burned
As consequence of the
broken the capacitors

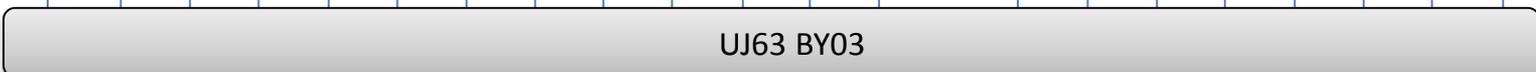
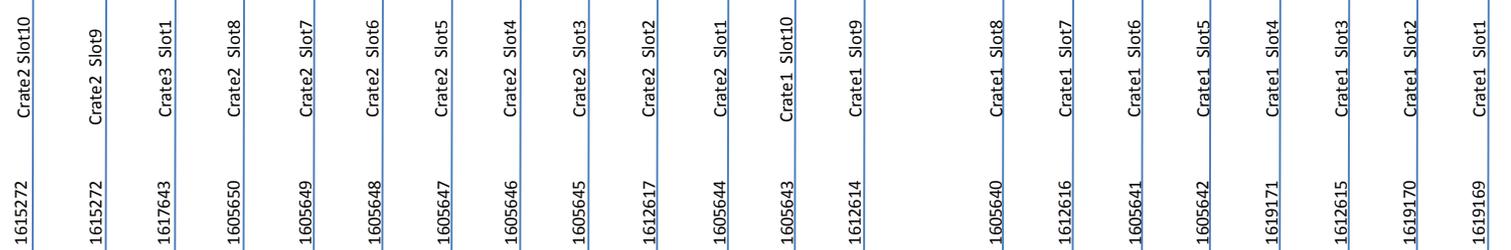
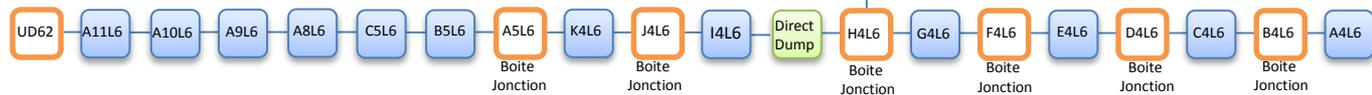


17 channels
12 BLECF to repair
1 HV Filter box replaced
8 Filter capacitors exchanged



8 input filter capacitors broken

1 channel



HT SEM Boite Junction Analog

Summary and foreseen actions

- Observations
 - Damage of several tunnel digitizer cards input circuits
 - Damage of filter components
 - Damage could not come from BLM equipment, because of the power needed for the damages, several tenth of ampere in 100 us
- Comparison with October event
 - It is assumed that causes for the ionisation chamber high voltage increase are identical
- Investigation
 - Try of determination of entry location of high voltage pulse by data analysis
 - From the Sunday event postmortem data are stored
- Action
 - Installation of a overvoltage protection on the tunnel cables
 - May preventive exchange of HV in IP6 cables during TS1